## **Power MOSFET**

# 40 V, 3 m $\Omega$ , 107 A, Single N-Channel

#### **Features**

- Small Footprint (3.3x3.3 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

## **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	40	V
Gate-to-Source Voltage	Э		$V_{GS}$	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	107	Α
Current R <sub>θJC</sub> (Notes 1, 3)	Steady	T <sub>C</sub> = 100°C		75	
Power Dissipation	State	T <sub>C</sub> = 25°C	P <sub>D</sub>	68	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		34	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	23	Α
Current R <sub>0JA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C		16	
Power Dissipation	State	T <sub>A</sub> = 25°C	P <sub>D</sub>	3.3	W
R <sub>θJA</sub> (Notes 1 & 2)		T <sub>A</sub> = 100°C		1.6	
Pulsed Drain Current $T_A = 25^{\circ}C$ , $t_p = 10 \mu s$			I <sub>DM</sub>	740	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	76	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 7 A)			E <sub>AS</sub>	215	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{ heta JC}$	2.2	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	46	

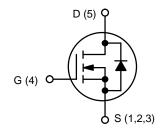
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



## ON Semiconductor®

#### www.onsemi.com

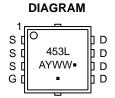
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
40 V	3 mΩ @ 10 V	107 /
40 V	4.8 mΩ @ 4.5 V	107 A



**N-CHANNEL MOSFET** 



## WDFN8 (μ8FL) CASE 511AB



**MARKING** 

453L = Specific Device Code A = Assembly Location

Y = Year WW = Work Week ■ = Pb-Free Package

(Note: Microdot may be in either location)

## ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 5 of this data sheet.

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				1.6		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V,$	T <sub>J</sub> = 25 °C			10	
		$V_{DS} = 40 \text{ V}$	T <sub>J</sub> = 125°C			250	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 63 μΑ	1.2		2.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.3		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 40 A		2.5	3	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 40 A		3.8	4.8	mΩ
Forward Transconductance	9 <sub>FS</sub>	$V_{DS} = 15 \text{ V}, I_{D}$	= 40 A		120		S
CHARGES AND CAPACITANCES							•
Input Capacitance	C <sub>ISS</sub>				2100		
Output Capacitance	Coss	$V_{GS} = 0 \text{ V, f} = 1 \text{ MHz, } V_{DS} = 25 \text{ V}$			1000		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				42		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 20 V; I <sub>D</sub> = 40 A			35		
Total Gate Charge	Q <sub>G(TOT)</sub>				16		1
Threshold Gate Charge	Q <sub>G(TH)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 20 \text{ V}; I_D = 40 \text{ A}$			4.0		nC
Gate-to-Source Charge	Q <sub>GS</sub>				7.0		
Gate-to-Drain Charge	$Q_{GD}$				5.0		
Plateau Voltage	$V_{GP}$				3.2		V
SWITCHING CHARACTERISTICS (Note 5	i)						
Turn-On Delay Time	t <sub>d(ON)</sub>				11		
Rise Time	t <sub>r</sub>	$V_{GS} = 4.5 \text{ V}, V_{D}$	s = 20 V,		110		ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$V_{GS} = 4.5 \text{ V}, V_{D}$ $I_{D} = 40 \text{ A}, R_{G} = 40 \text{ A}$	= 2.5 Ω		21		
Fall Time	t <sub>f</sub>				5		1 !
DRAIN-SOURCE DIODE CHARACTERIS	TICS						
Forward Diode Voltage	$V_{SD}$	$V_{GS} = 0 \text{ V},$ $I_S = 40 \text{ A}$ $T_J = 25^{\circ}\text{C}$ $T_J = 125^{\circ}\text{C}$			0.84	1.2	.,
					0.72		V
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 40 \text{ A}$			41		
Charge Time	ta				19		ns
Discharge Time	t <sub>b</sub>				22		1
Reverse Recovery Charge	$Q_{RR}$				30		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.

5. Switching characteristics are independent of operating junction temperatures.

## **TYPICAL CHARACTERISTICS**

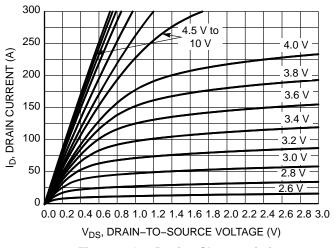


Figure 1. On-Region Characteristics

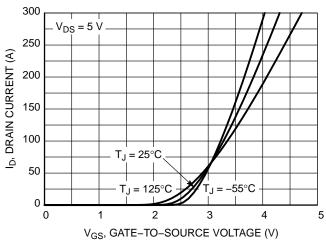


Figure 2. Transfer Characteristics

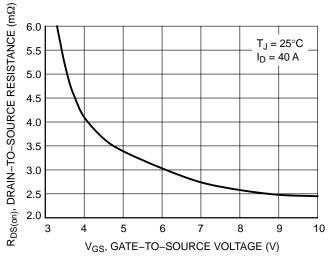


Figure 3. On-Resistance vs. Gate-to-Source Voltage

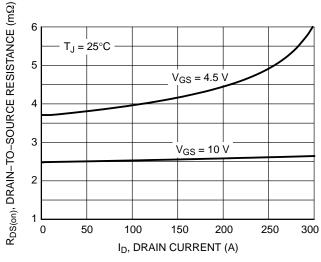


Figure 4. On–Resistance vs. Drain Current and Gate Voltage

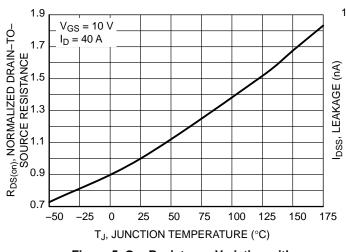


Figure 5. On–Resistance Variation with Temperature

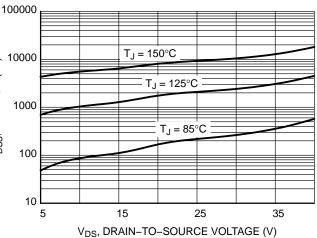
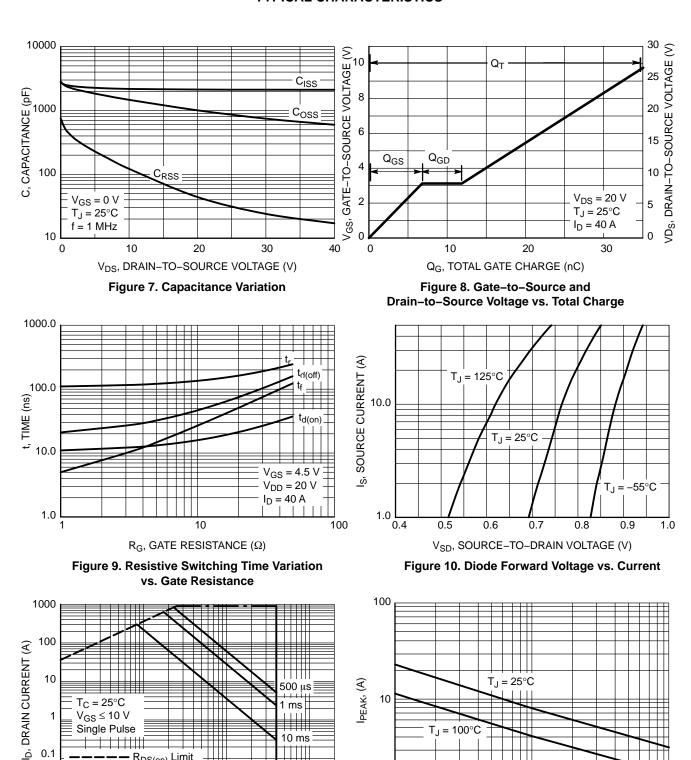


Figure 6. Drain-to-Source Leakage Current vs. Voltage

## **TYPICAL CHARACTERISTICS**



V<sub>DS</sub> (V) Figure 11. Safe Operating Area

10

R<sub>DS(on)</sub> Limit Thermal Limit Package Limit

Single Pulse

0.1

0.01

0.1

TIME IN AVALANCHE (s) Figure 12.  $I_{\mbox{\scriptsize PEAK}}$  vs. Time in Avalanche

1E-3

10E-2

 $T_{.1} = 100^{\circ}C$ 

1 L 1E-4

10 ms

100

## **TYPICAL CHARACTERISTICS**

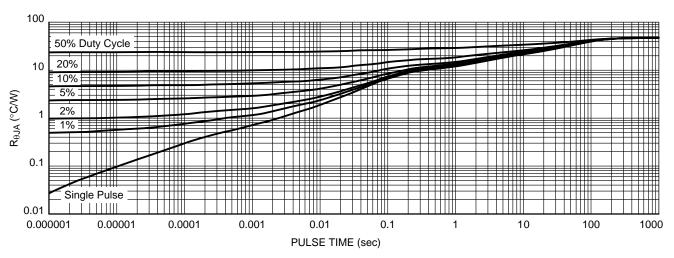


Figure 13. Thermal Characteristics

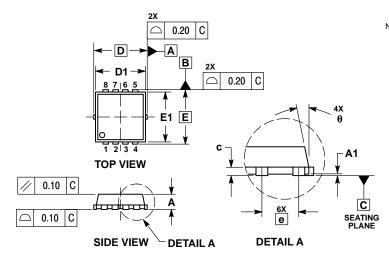
## **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NTTFS5C453NLTAG	453L	WDFN8 (Pb-Free)	1500 / Tape & Reel
NTTFS5C453NLTWG	453L	WDFN8 (Pb-Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS

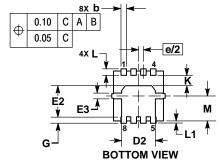
## WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D



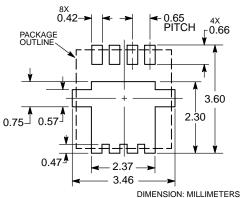
#### NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
   CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC		0	.130 BSC	)	
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E	3.30 BSC			0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е	0.65 BSC			0.026 BSC			
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
M	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	



#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ON Semiconductor and the (III) are registered trademarks of Semiconductor Components Industries, LLC (SCILLC) or its subsidiaries in the United States and/or other countries. SCILLC owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of SCILLC's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

## **PUBLICATION ORDERING INFORMATION**

## LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA **Phone**: 303–675–2175 or 800–344–3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910 Japan Customer Focus Center Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative